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Claims 1 – 5 (Cancelled).

6. (ORIGINAL) A method for testing integrated circuits comprising:
providing an excitation voltage to a device;
providing a power supply voltage to the device;
measuring the quiescent power supply current of the device;
changing the power supply voltage to the device; and
determining whether a change in quiescent power supply current of the device exceeds a predetermined allowable change.

7. (ORIGINAL) The method of claim 6 wherein the device is a field effect transistor.

8. (ORIGINAL) The method of claim 6 wherein changing the power supply voltage to the device comprises changing the power supply voltage to one or more predetermined voltages.

9. (ORIGINAL) The method of claim 6 wherein determining whether the change in quiescent power supply current of the device exceeds the predetermined allowable change comprises determining whether (|IDDQ(VCCmax) – IDDQ(VCCmin)|/(Min (IDDQ(VCCmax), IDDQ(VCCmin))) is less than a predetermined value.

10. (ORIGINAL) The method of claim 6 wherein measuring the quiescent power supply current of the device comprises:

determining whether the quiescent power supply current exceeds a maximum predetermined value; and

stopping subsequent testing if the quiescent power supply current exceeds the maximum predetermined value.

11. (ORIGINAL) The method of claim 6 further comprising generating notification data if the change in quiescent power supply current of the device exceeds the predetermined allowable change.

12. (ORIGINAL) A method for testing integrated circuits comprising:

providing an excitation voltage to a device;

providing a power supply voltage to the device;

measuring the quiescent power supply current of the device; and

changing the power supply voltage to the device if the quiescent power supply current is less than a predetermined value.

13. (ORIGINAL) The method of claim 12 further comprising stopping testing if the quiescent power supply current exceeds the predetermined value.

14. (ORIGINAL) The method of claim 12 wherein measuring the quiescent power supply current of the device further comprises waiting a predetermined period of time before measuring the quiescent power supply current of the device.

15. (ORIGINAL) The method of claim 12 wherein the device is a field effect transistor.

CLAIMS 16 THROUGH 28 ARE CANCELLED